

<b>Notice of References Cited</b>	Application/Control No. 10/767,376		Applicant(s)/Patent Under Reexamination DIAZ, NELSON	
	Examiner David S. Kim		Art Unit 2613	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-5,191,458 A	03-1993	Lyons et al.	398/79
*	B	US-5,422,643 A	06-1995	Chu et al.	341/141
*	C	US-5,568,143 A	10-1996	Hutchison et al.	341/139
*	D	US-6,255,974 B1	07-2001	Morizio et al.	341/143
*	E	US-6,373,423 B1	04-2002	Knudsen, Niels	341/159
*	F	US-6,417,965 B1	07-2002	Ye et al.	359/341.41
*	G	US-6,480,308 B1	11-2002	Yoshida et al.	398/16
*	H	US-2003/0048255 A1	03-2003	Choi et al.	345/166
*	I	US-6,760,552 B1	07-2004	Tajima et al.	398/210
*	J	US-6,934,470 B1	08-2005	Kunst et al.	398/38
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.